


<b>Search Notes</b>  	<b>Application/Control No.</b>  10542690	<b>Applicant(s)/Patent Under Reexamination</b>  ZHENG ET AL.
	<b>Examiner</b>  Danton DeMille	<b>Art Unit</b>  3771

SEARCHED			
Class	Subclass	Date	Examiner
601	41, 44, 148-152, Dig 20	10/26/09	/DDD/
242	147A	10/26/09	/DDD/

SEARCH NOTES		
Search Notes	Date	Examiner
text search, see printout	10/26/2009	/DDD/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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